

800G Optical Transceiver Tester MTP8104 I Datasheet V1.1

Integrated optical transceiver Bit Error Rate Tester (BERT) with field replaceable/MSA-compliant MCB, and temperature control unit based on TEC.

Applicable to the bit error analysis and Eye Diagram quality tests of 400G/800G optical transceiver under room, high and low temperature conditions.

Tailored to various industry standard pluggable transceiver packages, such as QSFP-DD, OSFP, QSFP112, etc.



Content

1	Product Description	.3
2	Key Features and Advantages	.4
	Flexible application	.4
	Comprehensive Capabilities	. 5
	Cost-effective	.6
	Fully Match ATE Application Scenarios	.6
3	Technical Specification	.7
	TX specification	.7
	RX specification	. 8
	Optical transceiver testing specification	.9
	Environment Specification	.9
4	Ordering Information	10
5	Warranty Terms	. 11

1 Product Description

Semight MTP8104 is a comprehensive Bit Error Rate Analysis system which integrates multi-channel Bit Error Rate Tester, multi-port MCBs to host optical transceiver, and multi-channel independent temperature control units, making it ideal for massproduced testing of high-speed 400G/800G optical transceiver across various ambient thermal cycle settings.

Utilizing the replaceable and MSA-compliant MCB, the MTP8104 can quickly and flexibly test pluggable transceivers without the need for additional high-speed RF cables. By simply changing the replaceable MCB and accessories, the MTP8104 is tailored to various industry standard pluggable transceiver packages, such as QSFP-DD, OSFP, QSFP112, etc.

The MTP8104 offers comprehensive coverage for various testing functions, including optical module BER test, FEC analyzer, transmitter calibration, DMI information monitor, voltage/current measurement, and vcc-bias tuner.

The integrated MCB is equipped with a appropriable TEC temperature-cycling crimping box kit. The cycling temperature range is $-10 \sim +85$ °C under no-load conditions, and $-5 \sim +85$ °C with loaded module DMI. The high-efficiency

temperature cycling test can be achieved benefiting from a water chiller with high cooling capacity.

Benefiting from its excellent signal quality (fast rise/fall time, low jitter), rich optional features (FEC analyzer, extendable data rates, etc), and high overall integration, the MTP8104 ensures strong performance and flexibility for the pre-research, design, and production testing of high-speed serial circuit products.

2 Key Features and Advantages

Flexible application

- > Wide Data Rate Range: 24.33~58Gbaud;
- Independent Control: Each channel can be independently configured with NRZ/PAM4, amplitude and equalization;
- > Flexible Switching: Input and output polarities can be switched flexibly;
- > Excellent Signal Quality: Rapid rise and fall time, low intrinsic jitter;
- Strong Output: Supports high-swing Output Amplitude, along with 3/7-tap pre-emphasis, Inner-Eye, and other transmission modulation;
- Rich Test Patterns: PRBS7~31Q; SSPRQ /JP03A /JP03B /LIN /Square

Wave/Custom Defined Patterns, etc;



- Versatile Trigger: Trigger output supports frequency divisions;
 supports software-controlled clock output switching;
- Parallel Testing: Support parallel BER/FEC/TEC control on each DUT channel by multiple ATEs;

800G Test Solution				
Model	Dut Type	Dut Amount		
NATD0104	400G/800G OSFP	4		
IVI I P8 104	400G/800G QSFP_DD	4		

Comprehensive Capabilities

- Support PCS hardware layer's FEC error correction analyzer;
- Support signal-to-noise ratio measurement;
- Support ultra-fast and high-precision BER sampling (<10ms);
- > Support multiple MSA optical module with

either Built-in or external IIC dongle for CMIS test;



Ultra-fast BER sampling mode (<10ms)



Cost-effective

- > Rich Accessories: Low maintenance costs like easy-replaceable MCBs;
- Flexible Configuration: Convenient configuration & replacement of accessories, which significantly reduces the overall testing cost;
- High integration: Low cost and high efficient three-temperature cycling solution with TEC;



Typical temperature cycling (-5~75, <3min)



Easy & flexible replaceable accessories

Fully Match ATE Application Scenarios

- > With powerful and flexible database management capabilities, it aids in the indepth analysis of data for research and development purposes.
- Can be remotely controlled via either Lan or USB port by invoking external APIs (LabVIEW, C#).



3 Technical Specification

TX specification

Туре	ltem	Description	
	Output	Differential PAM4/NRZ	
	Dut Amounts	4	
	Terminal	AC Coupling	
	output Impedance	100 Ω ± 10%	
	Pattern	PRBS 7/9/11/13/15/23/31, PRBS7~31Q; SSPRQ, JP03A, JP03B, LIN, Square Wave, Custom Defined Pattern, etc.;	
Pattern Generator Specification	Symbol Data Rate ^[1] (Gbaud)	24.33/24.8832/25/25.78125/26.5625/27.89/2 7.95/28.05/28.125/28.2/28.9/48.66/49.7664/5 1.5625/53.125/56/56.25/56.4/57.8/58	
	Frequence Accuracy	±50 ppm (typical)	
	Output Amplitude (Differential)	750 mVp-p (typical) ^[2]	
	Rise Time ^[3] (20–80%)	<10 ps (typical)	
	Fall Time ^[3] (20–80%)	<10 ps (typical)	
	Random Jitter ^[4]	<350 fs (typical)	
Trigger and Clock	Clock Output Amplitude	>300 mVp-p	
Specification	Output Type	AC Coupled, Single-end	

Туре	ltem	Description	
	Div Ratio (Adjustable)	4/8/16/32	
	Trigger Output	Built-in RF Switch to switch clock output	

[1] Option can be added to support expansion the rates <48G.

[2] Net measurement value at the transmitter's end, default pre-emphasis/de-emphasis parameters.

- [3] Tested with 53.125 Gbps NRZ signal.
- [4] Tested with/after Jitter separation.

RX specification

Туре	ltem	Description	
	Input	Differential PAM4 /NRZ	
	Terminal	AC Coupled	
	Input Impedance	100 Ω ±10%	
	Input Range (Differential) ^[1]	150 ~ 750 mVp-p (typical)	
Error Detector	RSSI (Differential) ^[1]	150 mVp-p (typical)	
specification	Pattern	PRBS 7/9/11/13/15/23/31, PRBS7~31Q;	
	Symbol Rate (Gbaud) ^[2]	24.33/24.8832/25/25.78125/26.5625/27.89/2 7.95/28.05/28.125/28.2/28.9/48.66/49.7664/5 1.5625/53.125/56/56.25/56.4/57.8/58	
	Clock Mode	Built-in Clock Recovery	
	Sync	Auto Sync (Level/Phase)	

[1] Take care of output amplitude from DUT as the high voltage signal may damage the receiver.

[2] Option can be added to support expansion the rates <48G.



Optical transceiver testing specification

Туре	ltem	Description
	TC Mode	Contact TEC temperature control
TC Specification	TC Range	-5 ~ + 85 °C [3]
[1][2]	Stability	±1 °C [4]
	Accuracy	±0.1 °C
Vcc Pigs Tupor	BIAS Range	3.069 ~ 3.5 V
VCC DIAS TUTIET	Step	1 mV

[1] The TC efficiency might fluctuate due to factors such as the ambient temperature, the power consumption of various transceivers, the location of heat sources, and the output power of the chiller.

- [2] Due to condensation by long-term low temperature use, the inner space should be circulated with dry and clean air, and periodically heated for drying.
- [3] Test environment: Room temperature of 25°C, 15W module placed in a closed space to reduce heat exchange with outside; Feedbacked by DMI temperature.
- [4] Perform repeat measurements of the temperature difference between the set temperature and case temperature.

Environment Specification

ltem	Description
Environment	Indoor
Operating	Temperature: 0°C to +55°C, Humidity: 30% to 80% @non-condensing



ltem	Description
Storage	Temperature: -30°C to 60°C, Humidity: 10% to 90%@non-condensing
Power Supply	Voltage Range: 100-240 VAC, Frequency Range: 50/60 Hz, Maximum Power: 800W
Warm-up	30-minutes of warm-up and automatic calibration, with the ambient temperature variation remaining within $\pm 3^{\circ}$ C
Dimensions (mm) ^[11]	171x585x442
Weight	32 kg (10.8lb) (Typical)

* Dimensions and weight may vary depending on the configuration of different options.

4 Ordering Information

Option Type	Option ID	Remarks
FEC	FEC	Integrated FEC analyzer, offering a graphical analysis interface as well as data management capabilities
Ext Data Rate	EDR	Extended protocol rates, refer to the specifications for details
DUTs	D01	Replaceable MCB, supports QSFP-DD/QSFPs
(Multiple choices)	D02	Replaceable MCB, support OSFP



	T01	TEC crimping component with QSFP-DD & QSFP packaging
Crimping box (Multiple choices)	Т02	TEC crimping component with OSFP-Finned Top packaging
	Т03	TEC crimping component with OSFP-RHS packaging
Service	R3C	Extended warranty and service plan - 36 months
(Choose one)	R5C	Extended warranty and service plan - 60 months

5 Warranty Terms

Number	Item	Description	Period
1	Mainframe Warranty Period	Free of Charge during the warranty period (excluding static electricity or human damage)	12 months
2	Calibration Period	Return to the factory for calibration or bring the calibration system for on-site calibration	24 months



Contact us

Semight Instruments Co. Ltd.

Mail sales@semight.com

Address

No. 1508 Xiangjiang Road, Suzhou, China

Web

Visit <u>www.semight.com</u> for more information.

* This information is subject to change without notice. © Semight Instrument, 2017-

2024, Published in China, 26-07-2024

